

Search Notes

Application/Control No.

10/801,219

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

MEGAW ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
323	312		
	313		
	314		
	315		
	316		
	907		
341	119		
327	539	1/09	JA

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR